

Notice of References Cited

Application/Control No.

09/836,711

Applicant(s)/Patent Under

Reexamination

WATANABE ET AL.

Examiner

Brian P. Egan

Art Unit

1772

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,827,445	10-1998	Yoshida et al.	252/62.54
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 00/19792	04-2000	PCT	Nakahoshi et al.	Translation Provided
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	S.H. HAN, et al.; Soft Magnetic Properties of Fe- (Si ₃ N ₄ , Al ₂ O ₃) Thin Films, IEEE Transactions on Magnetics, IEEE Inc., September 1996; Vol. 32, No.:5, pgs 4499-4501, New York,
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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